Application/Control No. Applicant(s)/Patent Under Reexamination 10/045,348 SHIN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2616 Mark A. Mais **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,400,730 06-2002 370/466 Latif et al. Α US-6,971,044 11-2005 Geng et al. 714/11 В С US-2002/0049825 04-2002 Jewett et al. 709/215 US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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